

## 60V N-Channel Enhancement Mode MOSFET

### Description

The AP60N06F uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 60V$   $I_D = 60A$

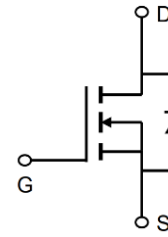
$R_{DS(ON)} < 15m\Omega$  @  $V_{GS}=10V$  (Type:11m $\Omega$ )

### Application

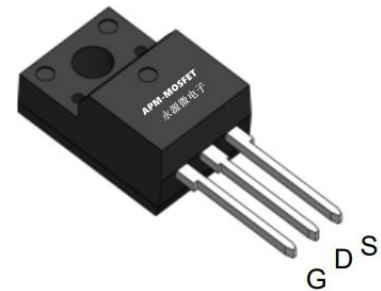
Battery protection

Load switch

Uninterruptible power supply



TO-220F



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP60N06F	TO-220F-3L	AP60N06F XXXX YYYY	1000

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	60	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D@T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	60	A
$I_D@T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10V^1$	35	A
IDM	Pulsed Drain Current <sup>2</sup>	180	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	39.2	mJ
IAS	Avalanche Current	38	A
$P_D@T_C=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	45	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	62.5	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	2.8	$^\circ\text{C/W}$

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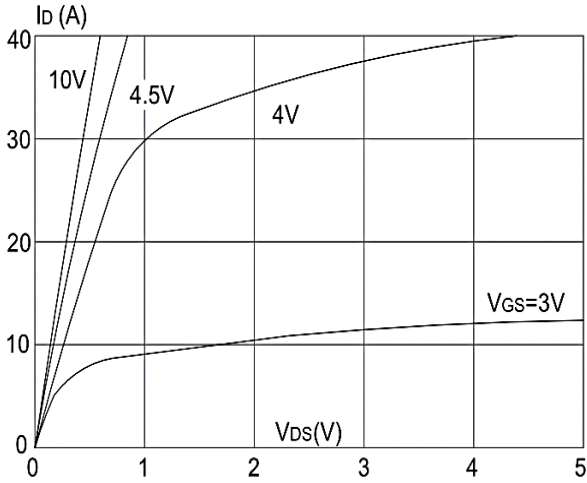
### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	60	65	---	V
ΔBVDSS/ΔT <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA	---	0.057	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	---	11	15	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A	---	16	20	
VGS(th)	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2	1.8	2.5	V
ΔVGS(th)	V <sub>GS(th)</sub> Temperature Coefficient		---	-5.68	---	mV/°C
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	---	---	1	uA
			---	---	5	
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	---	---	±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =15A	---	45	---	S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	---	1.7	---	Ω
Q <sub>g</sub>	Total Gate Charge (4.5V)	V <sub>DS</sub> =48V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A	---	19.3	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	7.1	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	7.6	---	
Td(on)	Turn-On Delay Time	V <sub>DD</sub> =30V, V <sub>GS</sub> =10V, R <sub>G</sub> =3.3Ω, I <sub>D</sub> =15A	---	7.2	---	ns
T <sub>r</sub>	Rise Time		---	50	---	
Td(off)	Turn-Off Delay Time		---	36.4	---	
T <sub>f</sub>	Fall Time		---	7.6	---	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz	---	2423	---	pF
C <sub>oss</sub>	Output Capacitance		---	145	---	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	97	---	
I <sub>s</sub>	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current	---	---	35	A
ISM	Pulsed Source Current <sup>2,5</sup>		---	---	80	A
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =A, T <sub>J</sub> =25°C	---	---	1	V
t <sub>rr</sub>	Reverse Recovery Time	IF=15A, di/dt=100A/μs, T <sub>J</sub> =25°C	---	16.3	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge		---	11	---	nC

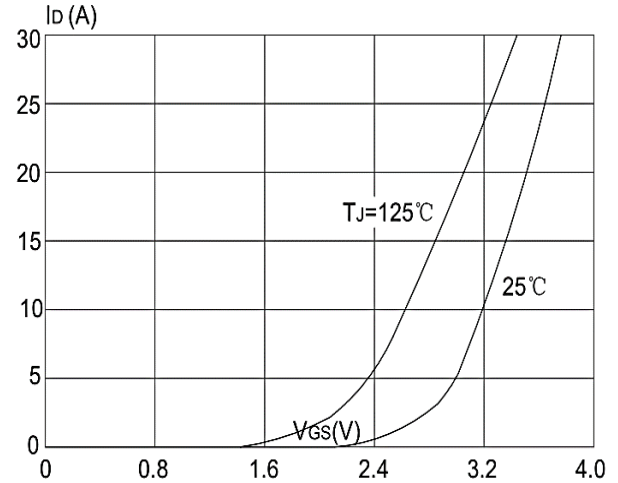
#### Note :

- 1、 The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=38A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

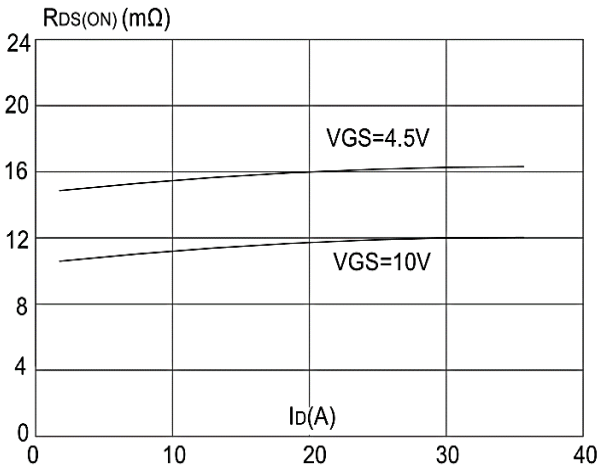
**Typical Characteristics**



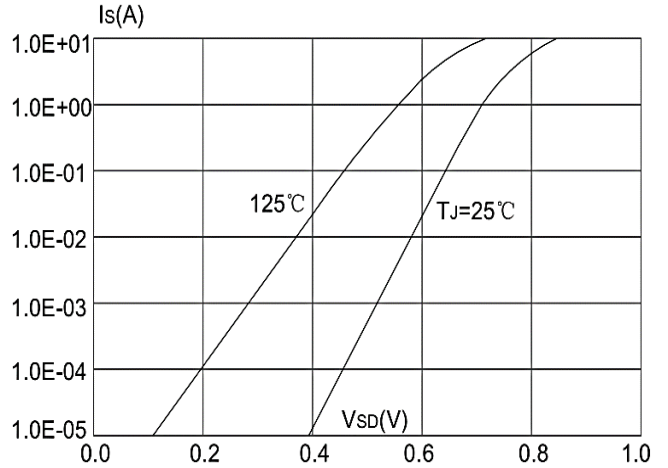
**Figure 1: Output Characteristics**



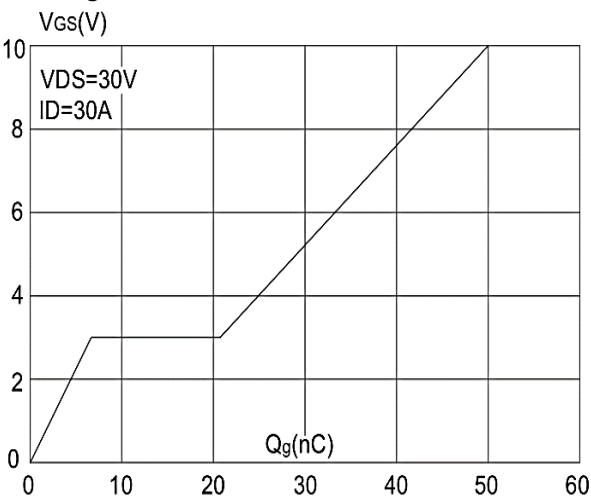
**Figure 2: Typical Transfer Characteristics**



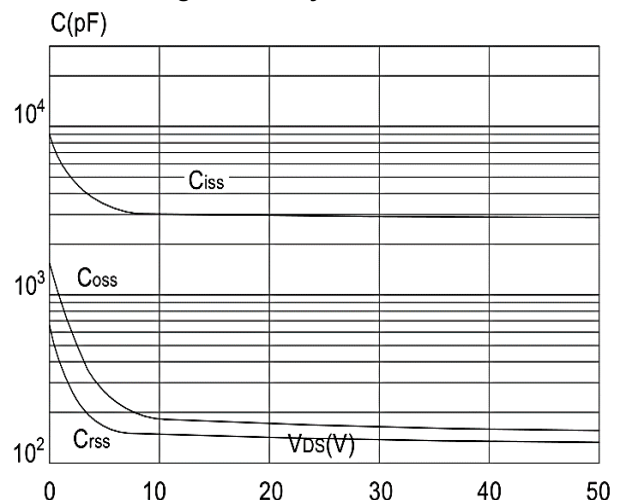
**Figure 3: On-resistance vs. Drain Current**



**Figure 4: Body Diode Characteristics**



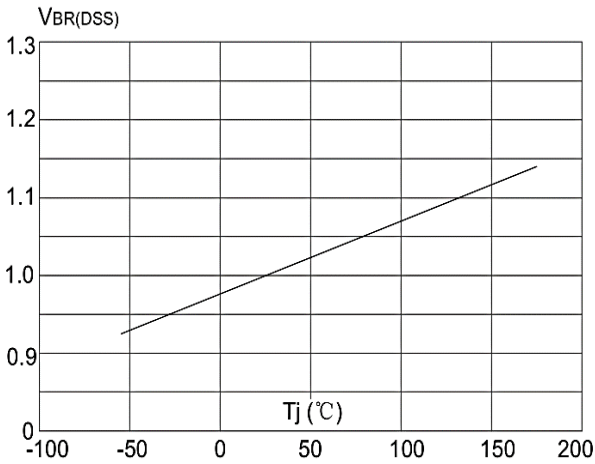
**Figure 5: Gate Charge Characteristics**



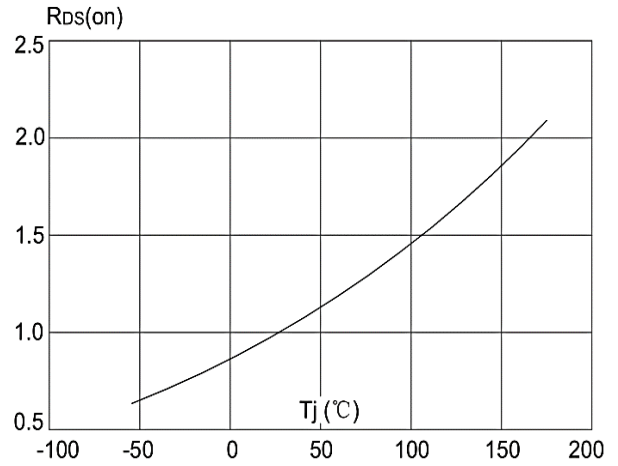
**Figure 6: Capacitance Characteristics**



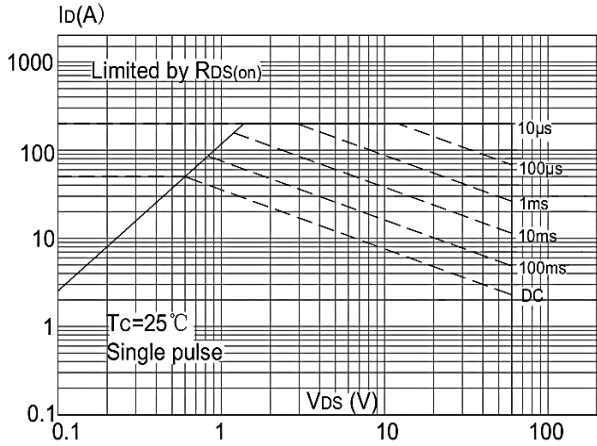
**60V N-Channel Enhancement Mode MOSFET**



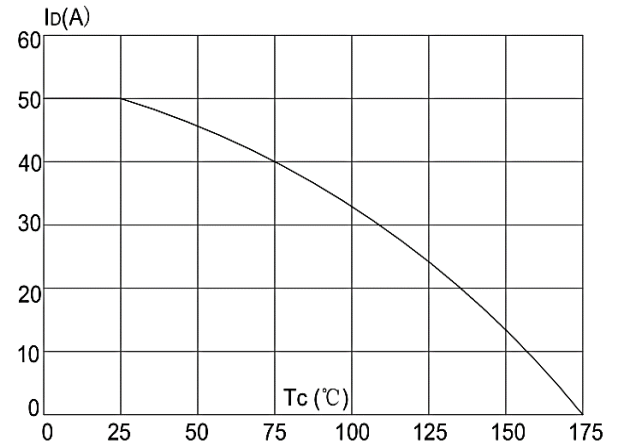
**Figure 7: Normalized Breakdown Voltage vs Junction Temperature**



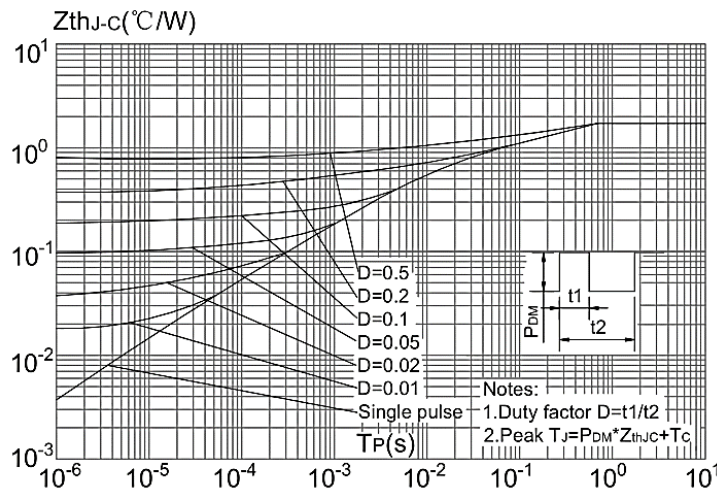
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area**

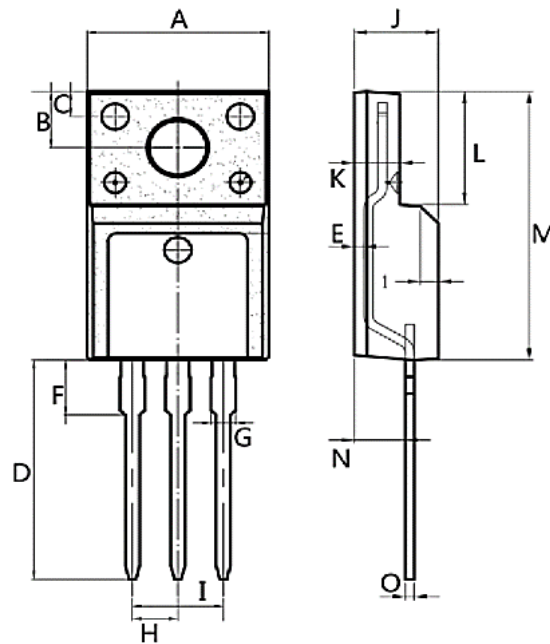


**Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature**



**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien**

### Package Mechanical Data-TO-220F-3L-



Symbol	Common	
	mm	
	Mim	Max
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	2.54	
I	5.08	
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

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## 60V N-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve1.0	2021/10/23	Initial release

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